74ABT541 Octal Buffer/Line Driver with 3-STATE Outputs

# FAIRCHILD

SEMICONDUCTOR

# 74ABT541 Octal Buffer/Line Driver with 3-STATE Outputs

## **General Description**

The ABT541 is an octal buffer and line driver with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/ receiver. The ABT541 is similar to the ABT244 with broad-side pinout.

# Features

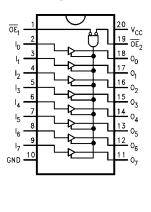
- Non-inverting buffers
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed output skew
- Guaranteed multiple output switching specifications
- Output switching specified for both 50 pF and 250 pF loads
- Guaranteed simultaneous switching, noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance, glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Flow-through pinout for ease of PC board layout
  Disable time less than enable time to avoid bus contention

#### **Ordering Code:**

Order Number	Package Number	Package Description
74ABT541CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT541CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT541CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT541CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74ABT541CPC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending suffix "X" to the ordering code.

#### **Connection Diagram**



#### **Pin Descriptions**

Pin Names	Description
$\overline{OE}_1, \overline{OE}_2$	Output Enable Input (Active LOW)
I <sub>0</sub> —I <sub>7</sub>	Inputs
0 <sub>0</sub> –0 <sub>7</sub>	Outputs

#### **Truth Table**

7

		Outputs
	2 1	
L L	Н	Н
н х	Х	Z
х н	х	Z
L L	L	L

# Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	$-55^{\circ}C$ to $+150^{\circ}C$
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disabled or	
Power-Off State	-0.5V to 5.5V
in the HIGH State	-0.5V to V <sub>CC</sub>
Current Applied to Output	
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	–500 mA
Over Voltage Latchup (I/O)	10V

# Recommended Operating Conditions

Free Air Ambient Temperature	-40°C to +85°C
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

# **DC Electrical Characteristics**

Symbol	Param	neter	Min	Тур	Max	Units	V <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Vo	oltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage		2.5			V	Min	I <sub>OH</sub> = -3 mA
			2.0			V	Min	$I_{OH} = -32 \text{ mA}$
V <sub>OL</sub>	Output LOW Voltage				0.55	V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current				1	μA	Max	V <sub>IN</sub> = 2.7V (Note 4)
					1	μΛ	IVIAA	$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current				7	μA Max		V <sub>IN</sub> = 7.0V
	Breakdown Test				,	μιτ	Max	
IIL	Input LOW Current				-1	μA	Мах	V <sub>IN</sub> = 0.5V (Note 4)
					-1	•	Max	$V_{IN} = 0.0V$
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
								All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Curre	ent			10	μΑ	0-5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Curre	ent			-10	μΑ	0-5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
los	Output Short-Circuit C	Current	-100		-275	mA	Max	$V_{OUT} = 0.0V$
I <sub>CEX</sub>	Output HIGH Leakage	e Current			50	μΑ	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test				100	μΑ	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Curren	t			50	μΑ	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Curren	t			30	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Curren	t			50	μΑ	Max	$\overline{OE}_n = V_{CC};$
								All Others at V <sub>CC</sub> or Ground
ICCT	Additional I <sub>CC</sub> /Input	Outputs Enabled			2.5	mA		$V_{I} = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
		Outputs 3-STATE			50	μA		Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V;
								All Others at V <sub>CC</sub> or Ground
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/		Outputs Open, $\overline{OE}_n = GND$ ,
	(Note 4)				0.1	MHz	Max	One Bit Toggling (Note 3),
								50% Duty Cycle

Note 3: For 8 bits toggling,  $I_{CCD} < 0.8$  mA/MHz.

Note 4: Guaranteed, but not tested.

# **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	$v_{cc}$	Conditions C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 $\Omega$
OLP	Quiet Output Maximum Dynamic V <sub>OL</sub>		0.7	1.0	V	5.0	$T_A = 25^{\circ}C$ (Note 5)
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	-1.3	-0.8		V	5.0	T <sub>A</sub> = 25°C (Note 5)
V <sub>онv</sub>	Minimum HIGH Level Dynamic Output Voltage	2.7	3.1		V	5.0	T <sub>A</sub> = 25°C (Note 6)
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	2.0	1.4		V	5.0	$T_A = 25^{\circ}C$ (Note 7)
/ <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.1	0.6	V	5.0	$T_A = 25^{\circ}C$ (Note 7)

Note 6: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

Note 7: Max number of data inputs (n) switching. n – 1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>ILD</sub>).

Guaranteed, but not tested.

## **AC Electrical Characteristics**

(SOIC and SSOP Package)

Symbol	Parameter	T <sub>A</sub> = +25°C V <sub>CC</sub> = +5V C <sub>L</sub> = 50 pF		$T_{A} = -40^{\circ}$ $V_{CC} = 4$ $C_{L} =$	Units		
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	1.0	2.0	3.6	1.0	3.6	20
t <sub>PHL</sub>	Data to Outputs	1.0	2.4	3.6	1.0	3.6	ns
t <sub>PZH</sub>	Output Enable Time	1.5	3.1	6.0	1.5	6.0	
t <sub>PZL</sub>		1.5	3.7	6.0	1.5	6.0	ns
t <sub>PHZ</sub>	Output Disable Time	1.7	3.5	6.1	1.7	6.1	20
t <sub>PLZ</sub>		1.7	3.1	5.6	1.7	5.6	ns

# **Extended AC Electrical Characteristics**

#### (SOIC Package) -40°C to +85°C V<sub>CC</sub> = 4.5V-5.5V

Symbol	Parameter	Parameter $V_{CC} = 4.5V-5.5V$ $V_{CC} = 4.5V-5.5V$ $C_L = 50 \text{ pF}$ $C_L = 250 \text{ pF}$ 8 Outputs Switching (Note 8) (Note 9)		C <sub>L</sub> = 50 pF 8 Outputs Switching		$V_{CC} = 4.5V-5.5V$ $C_L = 250 \text{ pF}$ 8 Outputs Switching (Note 10)		Units	
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>TOGGLE</sub>	Max Toggle Frequency		100						MHz
t <sub>PLH</sub>	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.5	
t <sub>PHL</sub>	Data to Outputs	1.5		5.0	1.5	6.0	2.5	8.5	ns
t <sub>PZH</sub>	Output Enable Time	1.5		6.5	2.5	7.5	2.5	9.5	
t <sub>PZL</sub>		1.5		6.5	2.5	7.5	2.5	10.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.0		6.1	(Niet	a (1)			
t <sub>PLZ</sub>		1.0		5.6	(INOL	e 11)			ns

 $T_A = -40^{\circ}C \text{ to } +85^{\circ}C$   $T_A = -40^{\circ}C \text{ to } +85^{\circ}C$ 

Note 8: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 9: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 10: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase

(i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 11: The 3-STATE delays are dominated by the RC network (5000, 250 pF) on the output and have been excluded from the datasheet.

74ABT541

www.fairchildsemi.com

(SOIC Pack		T <sub>▲</sub> = −40°C to +85°C	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	1
		$V_{CC} = 4.5V - 5.5V$	$V_{CC} = 4.5V - 5.5V$	
Symbol	Parameter	$C_L = 50 \text{ pF}$	$C_1 = 250  \text{pF}$	Units
		8 Outputs Switching	8 Outputs Switching	
		(Note 12)	(Note 13)	
		Max	Max	
t <sub>OSHL</sub> (Note 14)	Pin to Pin Skew, HL Transitions	1.3	2.3	ns
t <sub>OSLH</sub> (Note 14)	Pin to Pin Skew, LH Transitions	1.0	1.8	ns
t <sub>PS</sub> (Note 15)	Duty Cycle, LH/HL Skew	2.0	3.5	ns
<sup>t</sup> OST (Note 14)	Pin to Pin Skew, LH/HL Transitions	2.0	3.5	ns
t <sub>PV</sub> (Note 16)	Device to Device Skew, LH/HL Transitions	2.0	3.5	ns

Note 12: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)

Note 13: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

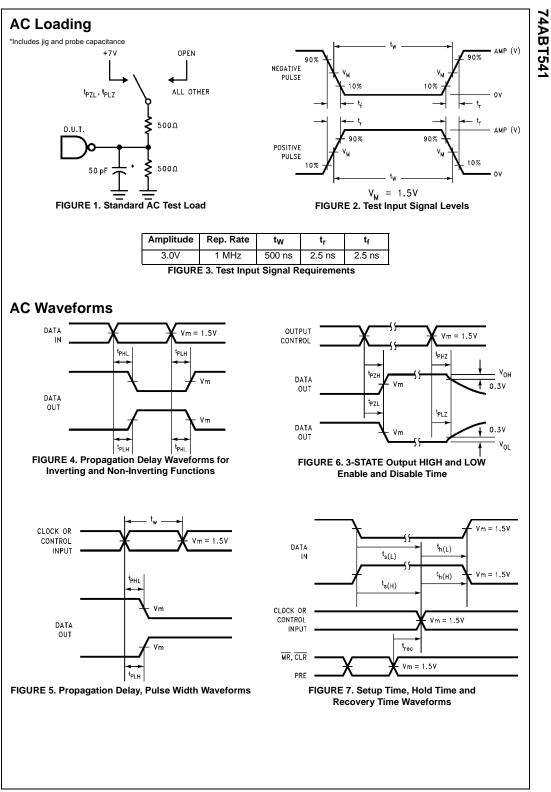
Note 14: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW (t<sub>OSHL</sub>), LOW-to-HIGH (t<sub>OSLH</sub>), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW (t<sub>OST</sub>). The specification is guaranteed but not tested.

Note 15: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. Note 16: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not tested.

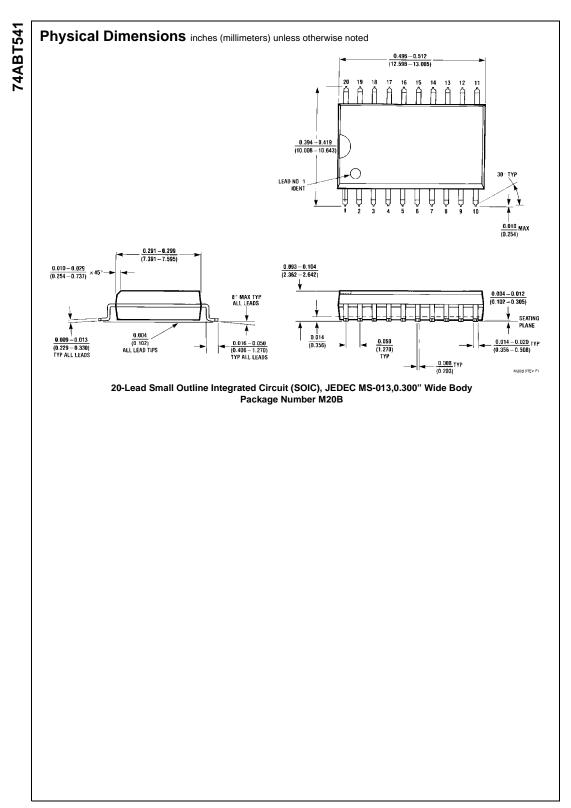
#### Capacitance

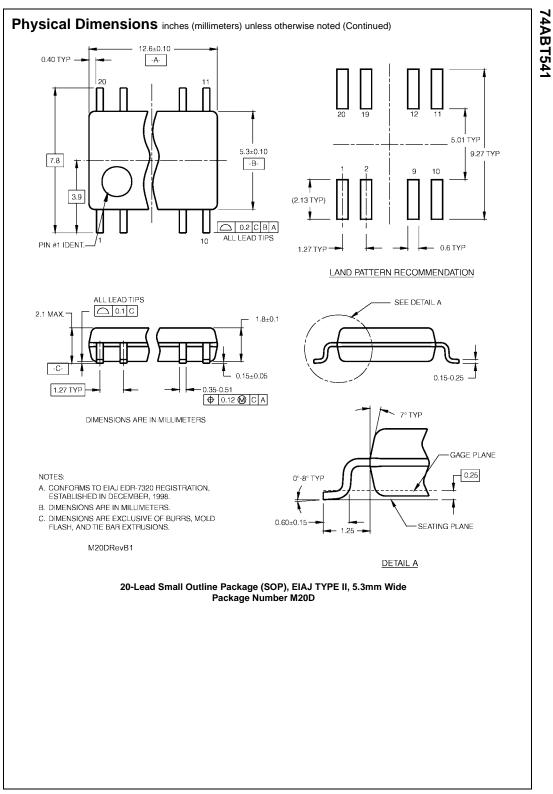
Querra ha a l	Deservator	Tree	Links.	Conditions T <sub>A</sub> = 25°C	
Symbol	Parameter	Тур	Units		
C <sub>IN</sub>	Input Capacitance	5.0	pF	$V_{CC} = 0.0V$	
C <sub>OUT</sub> (Note 17)	Output Capacitance	9.0	pF	$V_{CC} = 5.0V$	

Note 17:  $C_{OUT}$  is measured at frequency of f = 1 MHz, per MIL-STD-883, Method 3012.



www.fairchildsemi.com





www.fairchildsemi.com

